

6367254 MOTOROLA SC (XSTRS/R F)

96D 80603 D

T-33-07

MOTOROLA
SEMICONDUCTOR
TECHNICAL DATA

BD515
BD517
BD519

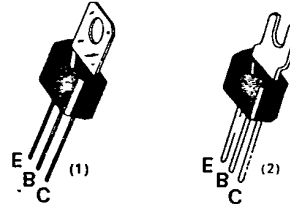
**NPN SILICON ANNULAR
AMPLIFIER TRANSISTORS**

... designed for general-purpose, high-voltage amplifier and driver applications.

- High Collector-Emitter Breakdown Voltage —
 $V_{CE0} = 45 \text{ Vdc (Min) @ } I_C = 1 \text{ mAdc — BD515}$
 $60 \text{ Vdc (Min) @ } I_C = 1 \text{ mAdc — BD517}$
 $80 \text{ Vdc (Min) @ } I_C = 1 \text{ mAdc — BD519}$
- High Power Dissipation — $P_D = 10 \text{ W @ } T_C = 25^\circ\text{C}$
- Complements to BD516, BD518, BD520

**NPN SILICON
AMPLIFIER TRANSISTORS**

45 - 60 - 80 VOLTS
10 WATTS



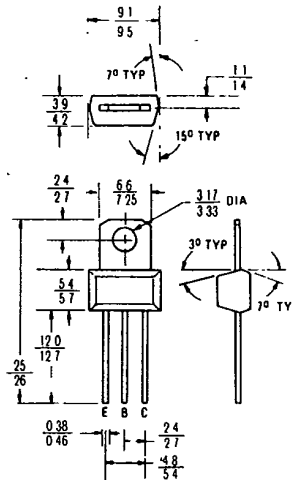
(1) Standard package BD515, 517, 519
 (2) Tab formed for flat mounting BD515 1, 517-1, 519-1
 Also available with leads formed to TO-5 configuration BD515-5, 517-5, 519-5

MAXIMUM RATINGS

| Rating | Symbol | BD515 | BD517 | BD519 | Unit |
|--|----------------|-------------|-------|-------|-------|
| Collector-Emitter Voltage | V_{CE0} | 45 | 60 | 80 | Vdc |
| Collector-Base Voltage | V_{CB} | 45 | 60 | 80 | Vdc |
| Emitter-Base Voltage | V_{EB} | 4.0 | | | Vdc |
| Collector Current — Continuous | I_C | 2.0 | | | Adc |
| Total Device Dissipation @ $T_A = 25^\circ\text{C}$ — Derate above 25°C | P_D | 1.0 | | | Watt |
| | | 8.0 | | | mW/°C |
| Total Device Dissipation @ $T_C = 25^\circ\text{C}$ — Derate above 25°C | P_D | 10 | | | Watts |
| | | 80 | | | mW/°C |
| Operating and Storage Junction Temperature Range | T_J, T_{stg} | -55 to +150 | | | °C |

THERMAL CHARACTERISTICS

| Characteristic | Symbol | Max | Unit |
|---|---------------|------|------|
| Thermal Resistance, Junction to Case | θ_{JC} | 12.5 | °C/W |
| Thermal Resistance, Junction to Ambient | θ_{JA} | 125 | °C/W |



All dimensions in millimeters
 Collector connected
 to tab

CASE 152

6367254 MOTOROLA SC (XSTRS/R F)

96D 80604 D

BD515, BD517, BD519

T-33-07

ELECTRICAL CHARACTERISTICS (T_C = 25°C unless otherwise noted)

| Characteristic | Symbol | Min | Typ | Max | Unit |
|--|-------------------------|----------------------|----------------|------------------|----------|
| OFF CHARACTERISTICS | | | | | |
| Collector-Emitter Breakdown Voltage (I _C = 1.0 mAdc, I _B = 0) | BD515 BD517 BD519 | BV _{CEO} | 45 60 80 | — — — | Vdc |
| Emitter-Base Breakdown Voltage (I _E = 100 μAdc, I _C = 0) | | BV _{EBO} | 4.0 | — | Vdc |
| Collector Cutoff Current (V _{CB} = 30 Vdc, I _E = 0) (V _{CB} = 40 Vdc, I _E = 0) (V _{CB} = 60 Vdc, I _E = 0) | BD515 BD517 BD519 | I _{CBO} | — — — | — — — | nAdc |
| ON CHARACTERISTICS | | | | | |
| DC Current Gain (1) (I _C = 10 mAdc, V _{CE} = 2.0 Vdc) (I _C = 150 mAdc, V _{CE} = 2.0 Vdc) (I _C = 500 mAdc, V _{CE} = 2.0 Vdc) | | h _{FE} | — 60 25 | 115 125 55 | — |
| Collector-Emitter Saturation Voltage (1) (I _C = 500 mAdc, I _B = 50 mAdc) (I _C = 500 mAdc, I _B = 25 mAdc) | | V _{CE(sat)} | — — | 0.18 0.24 | 0.5 — |
| Base-Emitter On Voltage (1) (I _C = 500 mAdc, V _{CE} = 2.0 Vdc) | | V _{BE(on)} | — | 0.74 | 1.0 |
| SMALL-SIGNAL CHARACTERISTICS | | | | | |
| Current-Gain-Bandwidth Product (I _C = 200 mAdc, V _{CE} = 5.0 Vdc, f = 100 MHz) | | f _T | 50 | 160 | — |
| Output Capacitance (V _{CB} = 10 Vdc, I _E = 0, f = 100 kHz) | | C _{ob} | — | 6.0 | 12 |

(1) Pulse Test. Pulse Width ≤ 300 μs, Duty Cycle ≤ 2.0%

FIGURE 1 — TYPICAL DC CURRENT GAIN

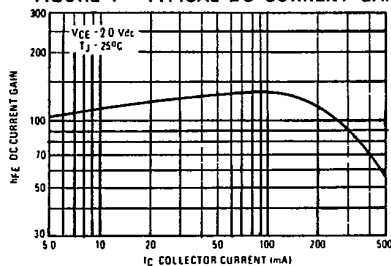


FIGURE 2 — "SATURATION" AND "ON" VOLTAGES

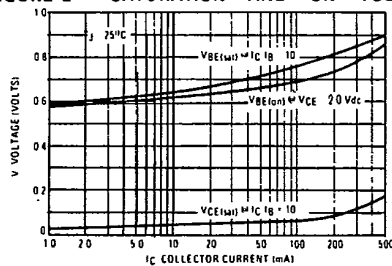


FIGURE 3 — DC SAFE OPERATING AREA

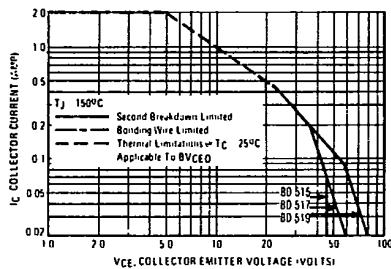
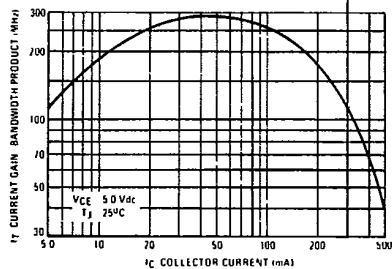


FIGURE 4 — CURRENT-GAIN — BANDWIDTH PRODUCT



There are two limitations on the power handling ability of a transistor junction temperature and secondary breakdown. Safe operating area curves indicate I_C - V_{CE} limits of the transistor that must be observed for reliable operation, i.e., the transistor must not be subjected to greater dissipation than the curves indicate.

The data of Figure 3 is based on T_J (pk) = 150°C. T_C is variable depending on conditions. At high case temperatures, thermal limitations will reduce the power that can be handled to values less than the limitations imposed by secondary breakdown.